

Notice of References Cited	Application/Control No. 10/790,931		Applicant(s)/Patent Under Reexamination TAKAYAMA ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0029597	03-2002	Choe et al.	72/53
	B	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	U	
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